EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp

| L1 | 91 | (US-20050104194-$ or US-20050002246-$ or US-20040038450-$ or US-20040026791-$ or US-20030207495-$ or US-20010026152-$ or US-20040145387-$ or US-20050099199-$ or US-20040230932-$ or US-20030061528-$ or US-20030137860-$ or US-20020109221-$ or US-20020064033-$ or US-20010049157-$ or US-20040178488-$ or US-20050153465-$ or US-20040164385-$).did. or (US-5414370-$ or US-5406212-$ or US-6703854-$ or US-6762486-$ or US-5998860-$ or US-4926117-$ or US-6006347-$ or US-5301155-$ or US-6246618-$ or US-6198663-$ or US-6288958-$ or US-6286118-$ or US-5781789-$ or US-5936977-$ or US-5953285-$ or US-6697978-$ or US-6161205-$ or US-6119255-$ or US-5461544-$ or US-5239747-$ or US-6754849-$ or US-6577979-$ or US-5519715-$ or US-6236952-$ or US-5892949-$ or US-5748532-$). did. or (US-5701309-$ or US-5459684-$ or US-5157664-$ or US-6680212-$ or US-6483333-$ or US-5243498-$ or US-5959310-$ or US-5931311-$ or US-6087676-$ or US-6091079-$ or US-5473259-$ or US-6728653-$ or US-6238942-$ or US-6016282-$ or US-5817535-$ or US-6395565-$ or US-6725115-$ or US-5956233-$ or US-6300163-$ or US-6214641-$ or US-6104089-$ or US-6091143-$ or US-5998865-$ or US-5899705-$ or US-5811879-$ or US-5723907-$ or US-6656767-$). did. or (US-6897553-$ or US-6884654-$ or US-6754129-$ or US-6707141-$ or US-6677671-$ or US-6465275-$ or US-6445063-$ or US-6329221-$ or US-6207474-$ or US-5936305-$ or US-6448524-$ or US-6357022-$ or US-6178526-$ or US-6055653-$ or US-6150724-$ or US-5852617-$ or US-6856009-$ or US-6014316-$ or US-6122760-$). did. or (KR-2004001017-$ or US-20020014913-$).did. | US-PGPUB; USPAT; DERWENT | OR | OFF | 2006/10/30 07:12 |

EAST Search History

S1	1	"20040145387"	US-PGPUB; USPAT	OR	ON	2006/03/16 14:17
S2	4876	324/765,158.1.ccls.	US-PGPUB; USPAT	OR	ON	2005/02/22 14:47
S3	2715	324/765.ccls.	US-PGPUB; USPAT	OR	ON	2005/02/22 14:47
S4	2651	324/158.1.ccls.	US-PGPUB; USPAT	OR	ON	2005/02/22 14:47
S5	490	S3 and S4	US-PGPUB; USPAT	OR	ON	2005/02/22 14:47
S6	42	S5 and load$4 and unload$4	US-PGPUB; USPAT	OR	ON	2005/02/22 14:48
S7	16	S5 and load$4 and unload$4 and sort$4	US-PGPUB; USPAT	OR	ON	2005/02/22 14:48
S8	1	"20040112142"	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:54
S9	1	"20010026152"	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:57
S10	2	"6462534"	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:52
S11	1	"20030115519"	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:03
S12	1	"20040119491"	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:44
S13	1	"20050007140"	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:04
S14	1	"20040207387"	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:46
S15	6	(bang near jeong).in. and scan	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:05
S16	13	(bang near jeong).in. and scan$4	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:06
S17	0	(bang near jeong).in. and scan$4 and burn adj in	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:48
S18	1	(bang near jeong).in. and scan$4 and burn$2in	US-PGPUB; USPAT	OR	OFF	2005/05/23 14:48
S19	0	(S8 S9 S10 S11 S12 S13 S14)	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:52
S20	0	(S8 S9 S10 S11 S12 S13 S14) scan	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:54
S21	0	S8 scan	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:54
S22	0	S9 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53

EAST Search History

S23	0	S8 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S24	0	S10 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S25	0	S11 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S26	0	S12 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S27	0	S13 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S28	0	S14 scan$4	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:53
S29	0	(S8 S9 S10 S11 S12 S13 S14) package	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:54
S30	1	S8 package	US-PGPUB; USPAT	AND	OFF	2005/05/23 14:55
S31	1	S8 package	US-PGPUB; USPAT	AND	ON	2005/05/23 14:55
S32	13	(bang near jeong).in. and scan$4	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:06
S33	3	(bang near jeong).in. and scan$4 and program	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:06
S34	3	(bang near jeong).in. and scan$4 and program	US-PGPUB; USPAT	OR	ON	2005/05/23 15:06
S35	1812	burn$1in and mask$4	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:20
S36	67	(burn$1in and mask$4).ab,clm.	US-PGPUB; USPAT	OR	OFF	2005/05/23 15:20
S37	10728	sram same dram	USPAT	OR	OFF	2005/05/23 17:30
S38	186	439/81.ccls.	USPAT	OR	OFF	2005/05/23 17:08
S39	511	sram same dram same test$4	USPAT	OR	OFF	2005/05/23 17:30
S40	28	sram same dram same test$4 same multiplex$4	USPAT	OR	OFF	2005/05/23 17:32
S41	733	365/201.ccls. and (mux multiplex$4)	USPAT	OR	OFF	2005/05/23 17:33
S42	123	365/201.ccls. and (mux multiplex$4) and sram and dram	USPAT	OR	OFF	2005/05/23 17:33
S43	18	365/201.ccls. and (mux multiplex$4) and sram and dram and burn$4	USPAT	OR	OFF	2005/05/23 17:48
S44	8	324/760.ccls. and test$4 with (different multiple) with types with semiconductor	USPAT	OR	OFF	2005/05/23 17:55

EAST Search History

S45	9	365/201.ccls. and test$4 with (different multiple) with types with semiconductor	USPAT	OR	OFF	2005/05/23 17:55
S46	7	(bang near jeong).in. and multiplex$4	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:08
S47	1103	multiplex$4 same masking	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:09
S48	44	multiplex$4 same masking and burn$4	US-PGPUB; USPAT	OR	OFF	2005/05/23 18:09
S49	37	(test$4 with multi$1chip).ti.	USPAT	OR	OFF	2005/05/25 15:11
S50	26	(test$4 with multi adj chip).ti.	USPAT	OR	OFF	2005/05/25 15:23
S51	25	S49 and S50	USPAT	OR	OFF	2005/05/25 15:08
S52	1	S50 not S51	USPAT	OR	OFF	2005/05/25 15:08
S53	4	(test$4 with multi$1chip with type).ti.	USPAT	OR	OFF	2005/05/25 15:09
S54	10	(test$4 with multi$1chip).ti. and burn-in	USPAT	OR	OFF	2005/05/25 15:11
S55	1	(test$4 with multi$1chip).ti. and burn adj in	USPAT	OR	OFF	2005/05/25 15:11
S56	0	(test$4 with multi adj chip).ti. and nurn-in	USPAT	OR	OFF	2005/05/25 15:21
S57	6	(test$4 with multi adj chip).ti. and burn-in	USPAT	OR	OFF	2005/05/25 15:21
S58	3	(test$4 with mcm).ti.	USPAT	OR	OFF	2005/05/25 15:24
S59	0	test$4 with different with temperature same multi adj cipp	USPAT	OR	OFF	2005/05/25 15:25
S60	0	test$4 with different with temperature same multi adj chip	USPAT	OR	OFF	2005/05/25 15:26
S61	0	test$4 with different with temperature same multi-chip	USPAT	OR	OFF	2005/05/25 15:26
S62	0	test$4 with different with temperature same mcm	USPAT	OR	OFF	2005/05/25 15:26
S63	0	test$4 with different with temperature same mcm	USPAT	OR	ON	2005/05/25 15:26
S64	0	test$4 with different with temperature same mcm	US-PGPUB; USPAT	OR	ON	2005/05/25 15:26
S65	1	test$4 with different with temperature same multi-chip	US-PGPUB; USPAT	OR	OFF	2005/05/25 15:26
S66	1	test$4 with different with temperature same multi adj chip	US-PGPUB; USPAT	OR	OFF	2005/05/25 15:26
S67	1	test$4 same different with temperature same multi adj chip	US-PGPUB; USPAT	OR	OFF	2005/05/25 15:27

EAST Search History

S68	0	test$4 same different with temperature same multi adj chip	USOCR	OR	OFF	2005/05/25 15:27
S69	0	test$4 same different with temperature same multi adj chip	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/25 15:27
S70	2	different with temperature same multi adj chip	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/07 14:04
S71	0	temperature same different with type with multi adj chip	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/25 15:28
S72	2	different with type with multi adj chip	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/25 15:29
S73	87	different with type with multi adj chip	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:29
S74	6	S73 and "324"/$.ccls.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:30
S75	7	("4556975").PN. OR ("6198663"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:39
S76	57	324/760.ccls. and (mcm (multi adj chip))	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:40
S77	5	324/760.ccls. and (mcm (multi adj chip)) and different with temperature	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:41
S78	52	S76 not S77	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:54
S79	132	257/48.ccls. and burn-in	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/25 15:54
S80	10	257/48.ccls. and burn-in and different with temperature	US-PGPUB; USPAT; USOCR	OR	ON	2005/05/25 15:54
S82	1	(SDRAM DRAM different temperature).clm.	US-PGPUB; USPAT	AND	ON	2005/05/26 16:55
S83	0	(SDRAM DRAM different with temperature).clm.	US-PGPUB; USPAT	AND	ON	2005/05/26 17:12
S84	23	(test$4 plurality with semiconductor different with temperature).clm.	US-PGPUB; USPAT	AND	ON	2005/05/26 17:00
S85	270	SDRAM DRAM different with temperature	US-PGPUB; USPAT	AND	ON	2005/05/26 17:16

EAST Search History

S86	0	SDRAM DRAM different with temperature	USOCR	AND	ON	2005/05/26 17:13
S87	1	SDRAM DRAM different with temperature	EPO; JPO; DERWENT; IBM_TDB	AND	ON	2005/05/26 17:13
S88	108	SDRAM DRAM module different with temperature	US-PGPUB; USPAT	AND	ON	2005/05/26 17:37
S89	77	SDRAM same DRAM module different with temperature	US-PGPUB; USPAT	AND	ON	2005/05/26 17:52
S90	47	testing adj mcm	US-PGPUB; USPAT	AND	ON	2005/05/26 17:52
S91	4	testing adj mcm sdram dram	US-PGPUB; USPAT	AND	ON	2005/05/26 18:06
S92	15	("5137836" | "5539752" | "5796746" | "5807762" | "5817535" | "5844803" | "5856923" | "5907492" | "5915231" | "5927512" | "6067507").PN. OR ("6238942"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/26 17:56
S93	0	testing adj muiti-chip adj module sdram dram	US-PGPUB; USPAT	AND	ON	2005/05/26 18:07
S94	0	testing adj multi-chip adj module sdram dram	US-PGPUB; USPAT	AND	ON	2005/05/26 18:07
S95	47	testing adj multi-chip adj module	US-PGPUB; USPAT	AND	ON	2005/05/26 18:07
S96	44	S95 not S90	US-PGPUB; USPAT	AND	ON	2005/05/26 18:07
S97	3	S95 S90	US-PGPUB; USPAT	AND	ON	2005/05/26 18:08
S98	91	S95 or S90	US-PGPUB; USPAT	AND	ON	2005/05/26 18:09
S99	22	S98 and different adj type	US-PGPUB; USPAT	AND	ON	2005/05/26 18:26
S101	20	(test$4 adj program) (different adj type) (mcm or multi-chip)	US-PGPUB; USPAT	AND	ON	2005/05/26 18:28
S102	5	(test$4 adj program) (different adj type) (mcm or multi-chip) temperature	US-PGPUB; USPAT	AND	ON	2005/05/26 18:31
S103	15	S101 not S102	US-PGPUB; USPAT	AND	ON	2005/05/26 19:07
S104	879	package with multiple with type	US-PGPUB; USPAT	AND	ON	2005/05/26 19:07
S105	0	package with multiple with type and dram and dsram and dimm	US-PGPUB; USPAT	AND	ON	2005/05/26 19:08

EAST Search History

S10 6	0	package with multiple with type and dram and sdram and dimm	US-PGPUB; USPAT	AND	ON	2005/05/26 19:08
S10 7	31	package with multiple with type same (dram or sdram or dimm)	US-PGPUB; USPAT	AND	ON	2005/05/26 19:15
S10 8	0	package with multiple with type same (dram or sdram or dimm) and program	US-PGPUB; USPAT	AND	ON	2005/05/26 19:15
S10 9	0	package with multiple with type same (dram or sdram or dimm) and programm	US-PGPUB; USPAT	AND	ON	2005/05/26 19:15
S11 0	5	package with multiple with type same (dram or sdram or dimm) and test$4	US-PGPUB; USPAT	AND	ON	2005/05/26 19:35
S11 1	4	(US-6214641-$ or US-5998865-$ or US-5817535-$ or US-5723907-$). did.	USPAT	OR	OFF	2005/05/26 19:31
S11 2	86	("4992849" | "4992850" | "4996587" | "5107328" | "5137836" | "5162947" | "5239198" | "5255156" | "5280192" | "5418687" | "5465470" | "5477082" | "5480840" | "5495398" | "5610767" | "5687028").PN. OR ("5723907" | "5817535" | "5998865" | "6214641").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/26 19:31
S11 3	0	S112 and sdram and dram and test$4 and program	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/26 19:32
S11 4	0	S112 and sdram and test$4 and program	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/26 19:32
S11 5	0	S112 and sdram and test$4 and program	US-PGPUB; USPAT; USOCR	OR	ON	2005/05/26 19:32
S11 6	0	S112 and test$4 and program	US-PGPUB; USPAT; USOCR	OR	ON	2005/05/26 19:32
S11 7	6	S112 and sdram and dram and test$4	US-PGPUB; USPAT; USOCR	OR	OFF	2005/05/26 19:33
S11 8	1	package with multiple with type same (dram or sdram) and test$4	US-PGPUB; USPAT	AND	ON	2005/05/26 19:39
S11 9	0	(test$4 with (simm or dimm) with sdram dram).ti.	US-PGPUB; USPAT	AND	ON	2005/05/26 19:40
S12 0	0	(test$4 with (simm or dimm)).ti.	US-PGPUB; USPAT	AND	ON	2005/05/26 19:40

EAST Search History

S12 1	9	(test$4 with (simm or dimm)).ab.	US-PGPUB; USPAT	AND	ON	2005/05/26 19:40
S12 2	0	257/777.ccls. and (sram with dram with non$1volatile)	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/07 14:06
S12 3	0	257/777.ccls. and (sram with dram or non$1volatile)	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/07 14:06
S12 4	0	257/777.ccls. and (sram with dram)	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/07 14:06
S12 5	6	257/777.ccls. and (sram with dram with non$1volatile)	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/07 14:06
S12 6	6	257/777.ccls. and (sram with dram with non$1volatile)	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:26
S12 7	0	257/777.ccls. and (sram with dram with test$4)	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:14
S12 8	386	(sram with dram with test$4)	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:14
S12 9	20	(sram with dram with test$4 with package$4)	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:14
S13 0	5	(sram with dram with test$4 with package$4 and temperature)	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:15
S13 1	32	("4503537" | "4513418" | "5255229" | "5297087" | "5375091" | "5381373" | "5390129" | "5424988" | "5535164" | "5557573" | "5563833" | "5577051" | "5590079" | "5592422" | "5610866" | "5615164" | "5619462" | "5629943" | "5633877" | "5638331" | "5654925" | "5657282" | "5659551" | "5668770").PN. OR ("6122760").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/10/07 14:19
S13 2	59	257/777.ccls. and (test$4).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:54
S13 3	0	257/777.ccls. and (test$4 with different with temperature).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:54

EAST Search History

S13 4	2	257/777.ccls. and (test$4 with temperature).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:42
S13 5	1	"6198663".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:47
S13 6	1	"5931311".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:47
S13 7	0	257/777.ccls. and (test$4 and different with temperature).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:55
S13 8	0	257/777.ccls. and (test$4 and program and temperature).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:55
S13 9	1	257/777.ccls. and (test$4 and program).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/07 14:55
S14 0	1	"6014316".pn.	USPAT	OR	OFF	2005/10/16 14:43
S14 1	74	mask$4 adj function with block$4	USPAT	OR	OFF	2005/10/16 17:18
S14 2	0	mask$4 adj function with block$4 and burn$1in	USPAT	OR	OFF	2005/10/16 17:18
S14 3	0	mask$4 adj function with block$4 and burn adj in	USPAT	OR	OFF	2005/10/16 17:18
S14 4	2	mask$4 adj function with block$4 and burn	USPAT	OR	OFF	2005/10/16 17:19
S14 5	13	mask$4 adj function with block$4 and test	USPAT	OR	OFF	2005/10/16 17:19
S14 6	25	mask$4 adj function with block$4 and test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:19
S14 7	31	mask$4 adj function with block$4 and test$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:19
S14 8	17	mask$4 adj function with block$4 and test$4 and (semiconductor or integrated)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:19

EAST Search History

S15 0	5	S145 and (semiconductor or integrated)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:22
S15 1	12	S148 not S150	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:27
S15 2	1	test adj program with block$4 adj function	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:28
S15 3	1	test adj program with block$4 adj function	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/16 17:28
S15 4	143	program with block$4 adj function	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:28
S15 5	61	program with block$4 adj function and (semiconductor or integrated)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:29
S15 6	36	program with block$4 adj function and (semiconductor or integrated) and test$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:31
S15 7	1	program with block$4 adj function and (semiconductor or integrated) and test$4 and burn$1in	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:29

EAST Search History

S15 8	41	program with block$4 adj function and package and test$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/16 17:30
S15 9	24	S156 and S158	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/16 17:30
S16 0	7	program with mask$4 adj function and (semiconductor or integrated) and test$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:58
S16 1	1	S159 and S160	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:31
S16 2	1	2004-362653.NRAN.	DERWENT	OR	OFF	2005/10/16 17:53
S16 3	1	kr2004001017a	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:59
S16 4	1	KR2004001017A	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/16 17:59
S16 5	1	"20040216006"	US-PGPUB; USPAT	OR	ON	2006/03/16 14:22
S16 6	3	"6563070"	US-PGPUB; USPAT	OR	ON	2006/03/16 14:23
S16 7	0	(test$4 with simm).ti.	USPAT	OR	OFF	2006/04/10 19:33
S16 8	0	(test$4 with dimm).ti.	USPAT	OR	OFF	2006/04/10 19:33

S169	115	(test$4 with dimm)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:33
S170	63	(test$4 with simm)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:33
S171	15	(test$4 near2 simm)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:33
S172	29	(test$4 near2 dimm)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:34
S173	40	S171 or S172	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:34
S174	0	S173 and different near temperature	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:34
S175	11	(different near temperature) and (simm or dimm)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:35
S176	147	(different near temperature) and (sram)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:38
S177	0	(different near temperature) with (sram)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:35
S178	95	S176 and (test$4 or burn-in)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:38

S17 9	95	(different near temperature) and (sram) and (test$4 or burn-in)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:39
S18 0	186	(different near temperature) and (sram) and (test$4 or burn-in)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:39
S18 1	91	S180 not S179	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 19:43
S18 2	8	S181 and mcm	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/10 20:04
S18 3	2	(("5239747") or ("5461544")).PN.	USPAT	OR	OFF	2006/04/10 20:14
S18 4	0	((uploading with program) and (mcm or sram or dram)).clm.	USPAT	OR	OFF	2006/04/10 20:15
S18 5	0	((upload$4 with program) and (mcm or sram or dram)).clm.	USPAT	OR	OFF	2006/04/10 20:15
S18 6	202	((upload$4 with program) and (mcm or sram or dram))	USPAT	OR	OFF	2006/04/10 20:15
S18 7	4	((upload$4 with program) with (mcm or sram or dram))	USPAT	OR	OFF	2006/04/10 20:18
S18 8	281	((load$4 with program) with (mcm or sram or dram))	USPAT	OR	OFF	2006/04/10 20:52
S18 9	3	((load$4 with program) with (mcm or sram or dram)).clm.	USPAT	OR	OFF	2006/04/10 20:39
S19 0	3	((load$4 with test$4 near program) with (mcm or sram or dram))	USPAT	OR	OFF	2006/04/10 20:49
S19 1	0	((load$4 with test$4 near program) with (mcm)).clm.	USPAT	OR	OFF	2006/04/10 20:49
S19 2	0	((upload$4 with test$4 near program) with (mcm)).clm.	USPAT	OR	OFF	2006/04/10 20:49
S19 3	0	((upload$4 with test$4 near program) with (module)).clm.	USPAT	OR	OFF	2006/04/10 20:49
S19 4	4	((load$4 with test$4 near program) with (module)).clm.	USPAT	OR	OFF	2006/04/10 20:49

S19 5	73	((load$4 with program) with (mcm or sram or dram)) and semiconductor	USPAT	OR	OFF	2006/04/10 21:04
S19 6	13	S195 and temperature	USPAT	OR	OFF	2006/04/10 21:05

| S19 7 | 91 | (US-20040145387-$ or US-20010026152-$ or US-20050099199-$ or US-20030061528-$ or US-20040230932-$ or US-20030137860-$ or US-20020109221-$ or US-20020064033-$ or US-20010049157-$ or US-20040026791-$ or US-20030207495-$ or US-20050104194-$ or US-20050002246-$ or US-20040038450-$ or US-20040178488-$ or US-20050153465-$ or US-20040164385-$).did. or (US-5414370-$ or US-6762486-$ or US-6680212-$ or US-5998860-$ or US-6856009-$ or US-6150724-$ or US-6006347-$ or US-5301155-$ or US-4926117-$ or US-6246618-$ or US-6703854-$ or US-5406212-$ or US-6288958-$ or US-6198663-$ or US-5953285-$ or US-5936977-$ or US-5781789-$ or US-6286118-$ or US-6697978-$ or US-6161205-$ or US-6119255-$ or US-5461544-$ or US-5239747-$ or US-6754849-$ or US-6577979-$ or US-5519715-$). did. or (US-6236952-$ or US-5892949-$ or US-5748532-$ or US-5701309-$ or US-5459684-$ or US-5157664-$ or US-6483333-$ or US-5243498-$ or US-5959310-$ or US-5931311-$ or US-6091079-$ or US-6728653-$ or US-6087676-$ or US-5473259-$ or US-6016282-$ or US-6395565-$ or US-5817535-$ or US-5956233-$ or US-6238942-$ or US-6725115-$ or US-6754129-$ or US-6897553-$ or US-6884654-$ or US-6707141-$ or US-6677671-$ or US-6656767-$ or US-6445063-$). did. or (US-6329221-$ or US-6300163-$ or US-6214641-$ or US-6091143-$ or US-5998865-$ or US-5936305-$ or US-5899705-$ or US-5811879-$ or US-5723907-$ or US-6465275-$ or US-6207474-$ or US-6104089-$ or US-6448524-$ or US-6357022-$ or US-6055653-$ or US-5852617-$ or US-6178526-$ or US-6122760-$ or US-6014316-$). did. or (KR-2004001017-$ or US-20020014913-$).did. | US-PGPUB; USPAT; DERWENT | OR | OFF | 2006/05/11 17:06 |

S19 8	0	S197 and tbga	USPAT	OR	OFF	2006/05/11 17:07
S19 9	34	"6014316"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 19:00
S20 0	0	S199 and tbga	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 17:07
S20 1	4578	bipolar near cmos	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 19:00
S20 2	735	(bipolar near cmos).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 19:02
S20 3	663	(bipolar near cmos).ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 19:02
S20 4	96	S202 and S203	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 19:02

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DBs | US-PGPUB; USPAT; DERWENT

Default operator: OR

☐ Plurals
☑ Highlight all hit terms initially

(US-20050104194-$ or US-20050002246-$ or US-20040038450-$ or US-20040026791-$ or US-20030207495-$ or US-20010026152-$ or US-20040145387-$ or US-20050099199-$ or US-20040230932-$ or US-20030061528-$ or US-20030137860-$ or US-20020109221-$ or US-20020064033-$ or US-20010049157-$ or US-20040178488-$ or US-20050153465-$ or US-20040164385-$).did. or (US-5414370-$ or US-5406212-$ or US-6703854-$ or US-6762486-$ or US-5998860-$ or US-4926117-$ or US-6006347-$ or US-5301155-$ or US-6246618-$ or US-6198663-$ or US-6288958-$ or US-6286118-$ or US-5781789-$ or US-5936977-$ or US-5953285-$ or US-6697978-$ or US-6161205-$ or US-6119255-$ or US-5461544-$ or US-5239747-$ or US-6754849-$ or US-6577979-$ or US-5519715-$ or US-6236952-$ or US-5892949-$ or US-5748352-$).did. or (US-5701309-$ or US-5459684-$ or US-5157664-$ or US-6680212-$ or US-6483333-$ or US-5243498-$ or US-5959310-$ or US-5931311-$ or US-6087676-$ or US-6091079-$ or US-5473259-$ or US-6728653-$ or US-6238942-$ or US-6016282-$ or US-5817535-$ or US-6395565-$ or US-6725115-$ or US-5956233-$ or US-6300163-$ or US-6214641-$ or US-6104089-$ or US-6091143-$ or US-5998865-$ or US-5899705-$ or US-5811879-$ or US-5723907-$ or US-6656767-$).did. or (US-6897553-$ or US-6884654-$ or US-6754129-$ or US-6707141-$ or US-6677671-$ or US-6465275-$ or US-6445063-$ or US-6329221-$ or US-6207474-$ or US-5936305-$ or US-6448524-$ or US-6357022-$ or US-6178526-$ or US-6055653-$ or US-6150724-$ or US-5852617-$ or US-6856009-$ or US-6014316-$ or US-6122760-$).did. or (KR-2004001017-$ or US-20020014913-$).did.

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	U	①	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Cla	Inventor	S	C	P		③	
1	☑	☑	US 20050153465 A1	20050714	35	Fabrication method of semiconductor integrated circuit device	438/14	714/724		Wada, Yuji et al.	☐	☐	☑	☐	☐	☐
2	☑	☑	US 20050104194 A1	20050519	10	CHIP PACKAGE STRUCTURE AND MANUFACTURING METHO	257/706	257/676; 257/707;		WENG, GWO-LIANG et al.	☐	☐	☑	☐	☐	☐
3	☑	☑	US 20050099199 A1	20050512	24	Semiconductor device and its test method	324/765	324/763; 438/14;		Sugita, Norihiko et al.	☐	☐	☑	☐	☐	☐
4	☑	☑	US 20050002246 A1	20050106	10	Memory module with integrated bus termination	365/200			Khatri, Dirgha et al.	☐	☐	☑	☐	☐	☐
5	☑	☑	US 20040230932 A1	20041118	16	Method for controlling semiconductor chips and control app	716/10	713/1; 713/100		Dickmann, Rory	☐	☐	☑	☐	☐	☐
6	☑	☐	US 20040178488 A1	20040916	15	Techniques for packaging multiple device components	257/686	257/723; 257/737;		Bolken, Todd O. et al.	☐	☐	☐	☐	☐	☑
7	☑	☑	US 20040164385 A1	20040826	54	Semiconductor device and manufacturing method thereof	257/678	257/777; 257/E23.079;		Kado, Yoshiyuki et al.	☐	☐	☑	☐	☐	☐
8	☑	☑	US 20040145387 A1	20040729	13	Integrated monitoring burn-in test method for multi-chip package	324/765			Yun, Geum-Jin et al.	☐	☐	☑	☐	☐	☐
9	☑	☑	US 20040038450 A1	20040226	16	Method of forming a stack of packaged memory dice	438/107	257/E25.023		King, Jerrold L. et al.	☐	☐	☑	☐	☐	☐
10	☑	☑	US 20040026791 A1	20040212	16	Apparatus for forming a stack of packaged memory dice	257/777	257/E25.023		King, Jerrold L. et al.	☐	☐	☑	☐	☐	☐
11	☑	☑	US 20030207495 A1	20031106	12	STACKED LEADS-OVER CHIP MULTI-CHIP MODULE	438/108	257/E21.512; 257/E23.004;		Akram, Salman	☐	☐	☑	☐	☐	☐

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